

Method and Apparatus for Online Hi-Pot Testing of Coatings

Disclosure Number

201102597

Technology Summary

Described is an apparatus and method for in-line hi-pot testing and selection and elimination of flawed material in electrically or electrochemically important components for applications. The technology allows for an in-situ observation of dielectric and electric parameters as a material is manufactured. An electrically conductive apparatus is used as the electrodes of the component inspection equipment. The material of interest is directed through the apparatus and if the material is determined to be flawed it can be marked and eliminated from further manufacturing, thus saving time and money.

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